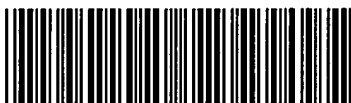


Search Notes

Application/Control No.

10/537,189

Examiner

Shih-Chao Chen

Applicant(s)/Patent under
Reexamination

WEN ET AL.

Art Unit

2821

SEARCHED

Class	Subclass	Date	Examiner
343	700MS, 702, 725, 770	7/24/2006	CHEN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
343	700MS	7/24/2006	CHEN
343	770	7/24/2006	CHEN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (Search updated).	7/24/2006	CHEN